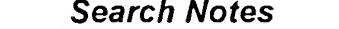


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/768,368	BUELOW ET AL.
	Examiner Jacob Y. Choi	Art Unit 2875

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner